Hybrid 8j263 Traveler

April 17, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J263 has die: 178-128 178-129 178-132 178-133 179-055 226-134 070-012 070-078

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j263 classification info. Created 08:59:07 04/12/00

Hybrid 8j263 quality: fair
Chip classification: good good good fair good good good good
Bad channels: none
Bad cells: none
Random bad capacitors (chip-cell-channel): 3-16-97 3-29-96 3-29-97
   3-3-96 3-3-97 3-30-97 3-33-96 3-33-97 3-34-97 3-36-96 3-36-97
   3-38-96 3-38-97 3-4-97 3-40-96 3-40-97
Channels at pedestal needed for DCMS: 33.5 32.7 32.7 30.7 32.6 33.6 34.6 33.6
```

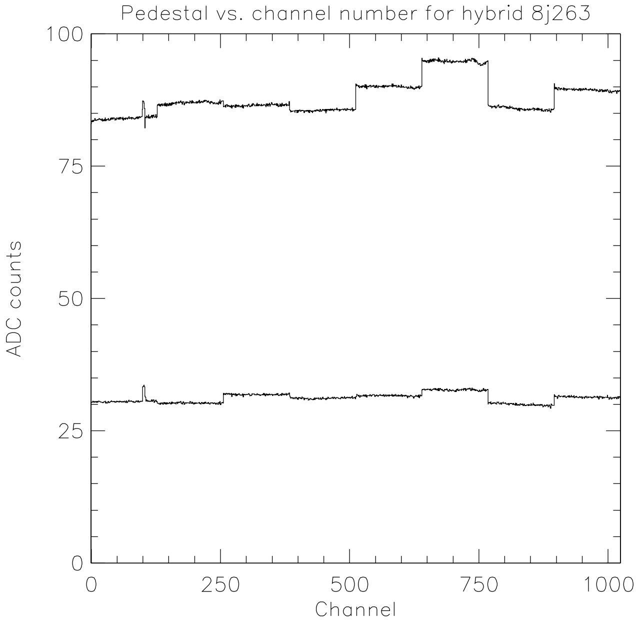
4 Comments

HV tested.

5 Pedestal

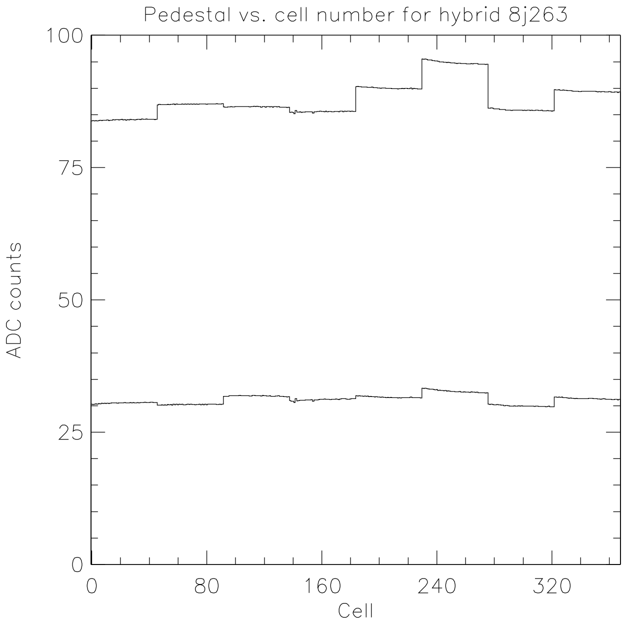
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

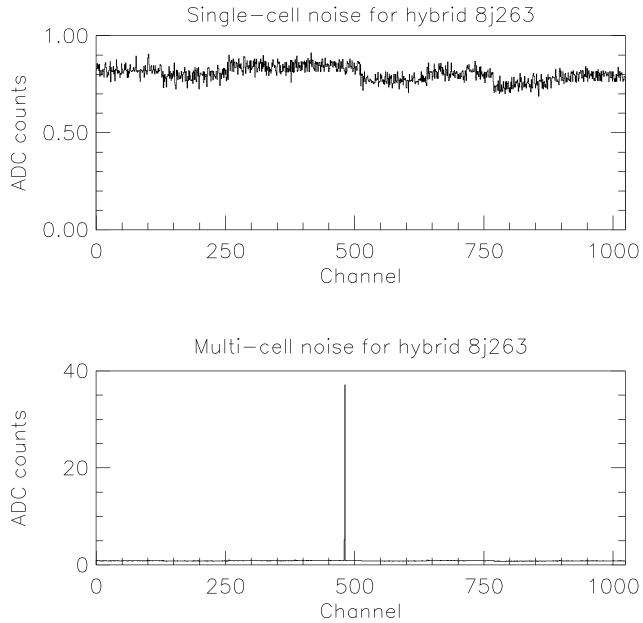
Pedestal vs. Pipeline Cell ID



6 Noise

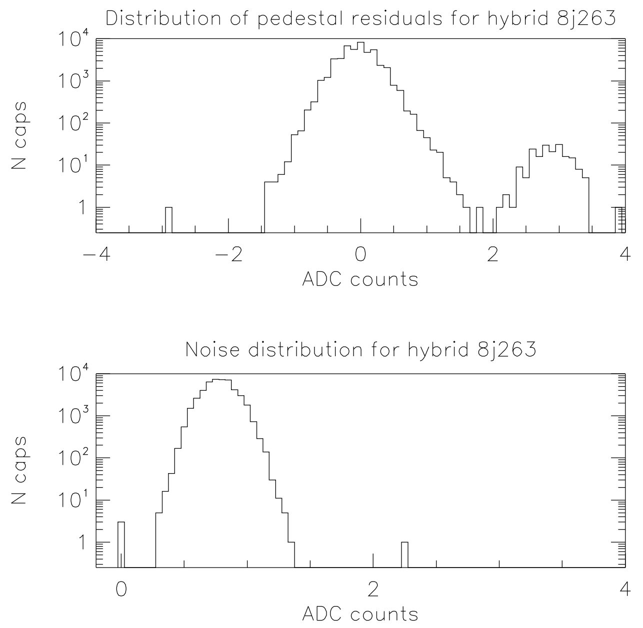
The following plots show the single-cell and multi-cell RMS noise:

RMS Noise



The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise



7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in